
IN THE UNITED STATES PATENT AND TRADEMARK OFFICE
(213.002-D1-US)

APPLICANT: Ye et al.

FILED: August 22, 2003

SERIAL NO.: 10/646,313

APR 15 2004

TITLE: System and Method for Lithography Process Monitoring
And Control

RECEIPT OF THE FOLLOWING PAPERS IS ACKNOWLEDGED

1. Second Information Disclosure Statement (1 page + 1 sheet of
Modified Form PTO-1449 + Reference cited therein)

DATE: April 12, 2004

[Check No. N/A]

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE
(Case No. 213.002-D1-US)

In the Application of: **Ye et al.**

Serial No: **10/646,313**

Filed: **August 22, 2003**

Title: **SYSTEM AND METHOD FOR LITHOGRAPHY
PROCESS MONITORING AND CONTROL**

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

) Group Art Unit:

) Before Examiner

I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail with sufficient postage in an envelope addressed to the Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450 on April 12, 2004.

Date

Michiko Sides
(person signing this certificate)

Neil A. Steinberg
Signature

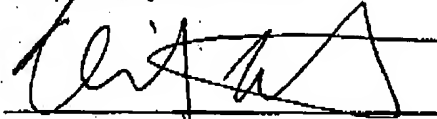
SECOND INFORMATION DISCLOSURE STATEMENT

Dear Sir:

Submitted herewith is one (1) sheet of a modified Form PTO-1449. A copy of the document cited on the attached Form PTO-1449 is also submitted.

It is respectfully requested that the Examiner make his/her consideration of the document formally of record with the initial Office Action.

Respectfully submitted,



Neil A. Steinberg
Reg. No. 34,735
650-968-8079

Date: April 12, 2004

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| PTO-1649 (Modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT BY APPLICANT | ATTY. DOCKET NO. 213.002-D1-US | | Sheet 1 of 1 SERIAL NUMBER 10/648,313 |
| | APPLICANT(S) Ye et al. | | |
| | FILING DATE August 22, 2003 | GROUP ART UNIT | |
| | (This area is left blank for the applicant's use.) | | |

U.S. PATENT DOCUMENTS

| U. S. PATENT DOCUMENTS | | | | | | |
|------------------------|--------------------|------|------|-------|--------------|----------------|
| EXAMINER INITIALS | DOCUMENT NUMBER | DATE | NAME | CLASS | SUB CLASS | FILING DATE |
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FOREIGN PATENT DOCUMENTS

| FOREIGN PATENT DOCUMENTS | | | | | | |
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| EXAMINER INITIALS | DOCUMENT NUMBER | DATE | COUNTRY | CLASS | SUB CLASS | TRANSLATION YES/NO |
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OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

[illegible]

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|---|-----------------|
| EXAMINER | DATE CONSIDERED |
| <p>EXAMINER: Initial citation if reference was considered. Draw line through citation if not in conformance to MPEP 609 and not considered. Include copy of this form with next communication to applicant.</p> | |